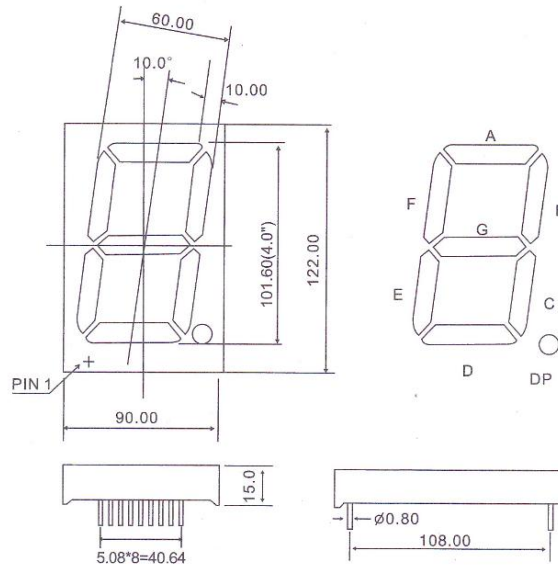


Product Data Sheet

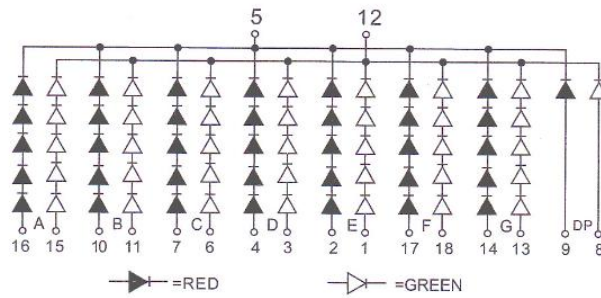
- ✧ KL40011WDBBSRPG
- ✧ Digit height:4.0 inch (101.60mm)
- ✧ Digit number: 1 digit
- ✧ Emitting color:Super red+Pure green

Dimension and Diagram

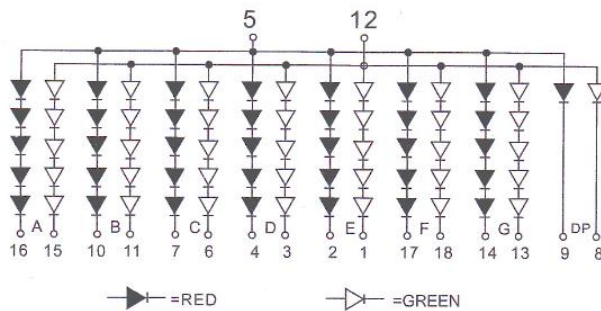
WD40011
(原:R40011)



PCB:D40011G/HEG



PCB:D40011G/HEG



Notes:

1. Dimension in millimeter [inch], tolerance is $\pm 0.25\text{mm}$ [$.01''$] and angle is $\pm 1^\circ$ unless otherwise noted.
2. Bending \leq Length*1%.
3. The specifications characteristics and technical data described in the datasheet are subject to change without prior notice.

Absolute Maximum Ratings at TA=25 °C

Parameter	Symbol	Test Condition	Value		Unit
			Min	Max	
Reverse Voltage	VR	IR=30	5	—	V
Forward Current	IF	—	—	20	mA
Power Dissipation	Pd	—	—	100	mW
Pulse Current	Ipeak	Duty=0.1mS,1KHz	—	150	mA
Operating Temperature	T opr	—	-40	+85	°C
Storage Temperature	T str	—	-40	+85	°C

Electro-Optical Characteristics (Ta=25 °C) For Pure green

Parameter		Symbol	Min.	Typ.	Max.	Units	Condition
Forward Voltage	Per segment	VF	--	14	15	V	IF=20mA
	Per decimal point			2.8	3.1		
Reverse Current		IR	--	--	10	μA	VR=5V
Luminous Intensity	Per segment	IV	1300	1400	1500	mcd	IF=20mA
	Per decimal point		260	280	300		
Peak Wavelength		λp	--	525	--	nm	IF=20mA
Dominant Wavelength		λd	--	520	--	nm	IF=20mA
Spectrum Radiation Bandwidth		Δλ	--	20	--	nm	IF=20mA

Electro-Optical Characteristics (Ta=25 °C) For Super red

Parameter		Symbol	Min.	Typ.	Max.	Units	Condition
Forward Voltage	Per segment	V _F	--	9	10	V	I _F =20mA
	Per decimal point			1.8	2		
Reverse Current		I _R	--	--	10	μA	V _R =5V
Luminous Intensity	Per segment	I _V	500	600	650	mcd	I _F =20mA
	Per decimal point		100	120	130		
Peak Wavelength		λ _p	--	625	--	nm	I _F =20mA
Dominant Wavelength		λ _d	--	620	--	nm	I _F =20mA
Spectrum Radiation Bandwidth		Δλ	--	20	--	nm	I _F =20mA

Note:

- 1.Luminous Intensity is based on the Kinley standards.
- 2.Pay attention about Intensity is only for one chip

Reliability test items and conditions:

The reliability of products shall be satisfied with items listed below. Confidence level:90% LTPD:10%

NO	Item	Test Conditions	Test Hours/Cycle	Sample Size	Failure Judgment Criteria	Ac/Re
1	Reflow Soldering	TEMP:230 °C±5 °C Min. 5 SEC	6 Min	22 PCS	$I_v \leq I_{vt} * 0.5$ or $V_F \geq U$ or $V_F \leq L$	0/1
2	Temperature Cycle	H:+100°C 15min ∫ 5min L:-40 °C 15min	300 Cycles	22 PCS		0/1
3	Thermal Shock	H:+100°C 5min ∫ 10 sec L:-10 °C 5min	300 Cycles	22 PCS		0/1
4	High Temperature Storage	TEMP:100 °C	1000 HRS	22PCS		0/1
5	Low Temperature Storage	TEMP:-40 °C	1000 HRS	22 PCS		0/1
6	DC Operating Life	TEMP:25 °C If=10mA	1000 HRS	22 PCS		0/1
7	High Temperature / High Humidity	85 °C / 85% RH	1000 HRS	22 PCS		0/1

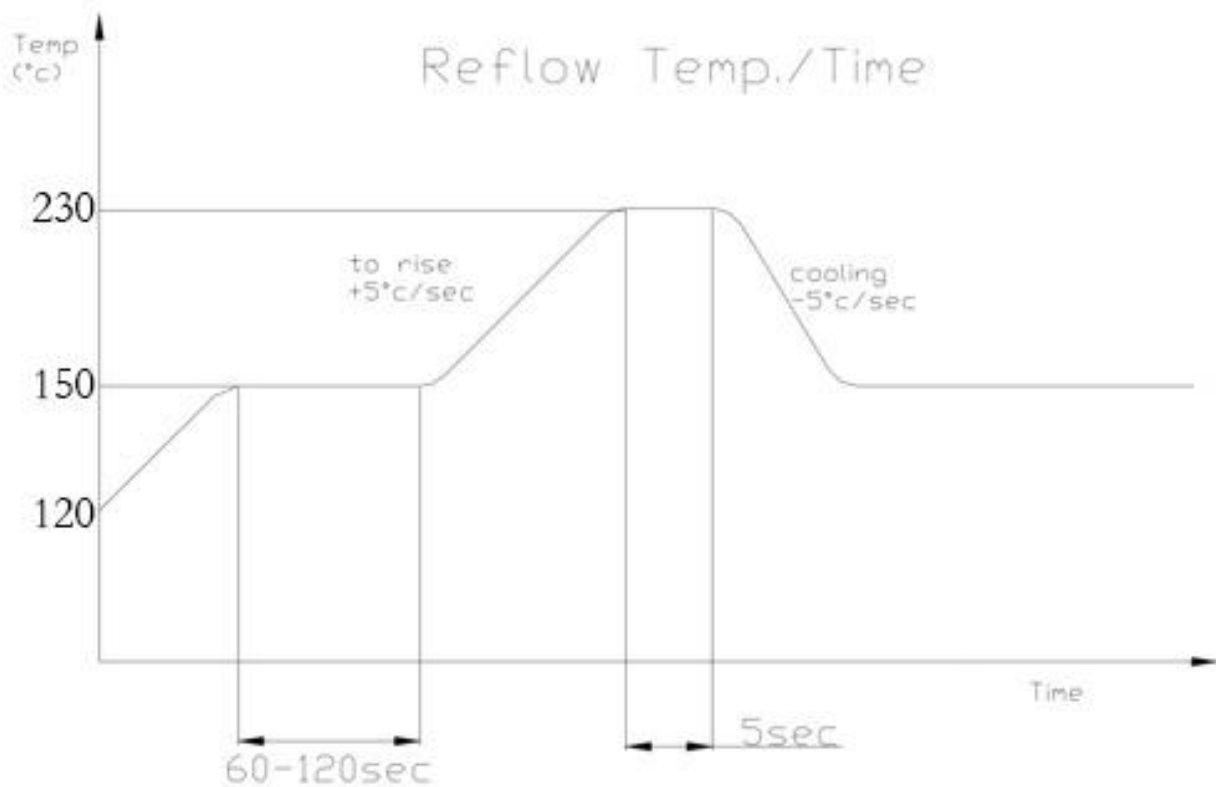
Note:

I_{vt}: The test I_v value of the chip before the reliability test

I_v: The test value of the chip that has completed the reliability test

U: Upper Specification Limit L: Lower Specification Limit

Reflow Temp. / Time :



■ Soldering Iron :

Basic spec is ≤ 5 sec when 230 °C. If temperature is higher, time should be shorter (+10°C → -1sec).

Power dissipation of iron should be smaller than 15 W, and temperature should be controllable. Surface temperature of the device should be under 230 °C.

■ Rework :

1. Customer must finish rework within 5 sec under 230 °C.
2. The head of iron can not touch copper foil.